



COLLOQUIUM -DEPARTMENT OF PHYSICS

THURSDAY - FEBRUARY 22, 2007 AT 5:00 PM

REFRESHMENTS WILL BE SERVED AT 4:30PM

PLACE: NURSING AMPHITHEATER, NU 113

TITLE: "Novel Applications of X-ray Diffraction Analysis"

Prof. I. Cevdet Noyan

Materials Science Program

Department of Applied Physics and Applied Mathematics,

School of Engineering and Applied Science

Columbia University, New York, NY 10027

Abstract- I will describe measurement of lattice spacing, line broadening and topographic intensity from nanomaterials, single crystals and polycrystalline materials using x-ray diffraction and discuss the limits on the interpretation of such data.

Host: Prof. M. Alper Sahiner, Physics Dept.

Contact: 973 761 9060, or sahineme@shu.edu for further information.